

Signetics

FAST Products

FEATURES

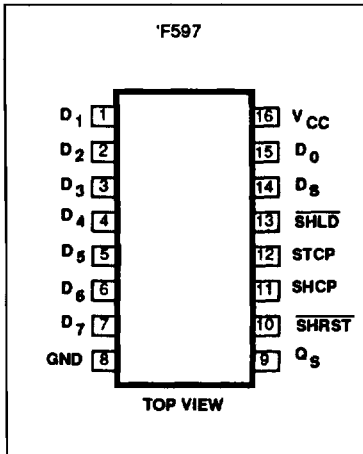
- High impedance NPN base input for reduced loading (20 μ A in High and Low states)
- 8-bit Parallel storage register
- Shift register has asynchronous direct overriding load and reset
- Guaranteed shift frequency DC to 120MHz
- Parallel 3-State I/O, Storage register inputs
- Shift register outputs-'F598

DESCRIPTION

The 74F597 consists of an 8-bit storage register feeding a parallel-in, serial out 8-bit shift register. The storage register and shift register have separate positive edge triggered clocks. The shift register also has asynchronous direct load (from storage) and reset inputs.

The 74F598 consists of an 8-bit storage register feeding a parallel/serial-in, parallel/serial out 8-bit shift register. Both the storage register and shift register have positive edge triggered clocks. The shift register also has asynchronous direct load (from storage) and reset inputs. The 'F598 has 3-state I/O ports that provide parallel shift register outputs and also has multiplexed serial data input.

PIN CONFIGURATION



February 16, 1989

FAST 74F597, 74F598 Shift Registers

74F597 8-Bit Shift Register with Input Latches

74F598 8-Bit Shift Register with Input Latches (3-State)

Preliminary Specification

TYPE	TYPICAL f_{MAX}	TYPICAL SUPPLY CURRENT (TOTAL)
74F597	120MHz	75mA
74F598	120MHz	75mA

ORDERING INFORMATION

PACKAGES	COMMERCIAL RANGE $V_{CC} = 5V \pm 10\%$; $T_A = 0^\circ C$ to $+70^\circ C$
16-Pin Plastic DIP	N74F597N
20-Pin Plastic DIP	N74F598N
16-Pin Plastic SO	N74F597D
20-Pin Plastic SOL	N74F598D

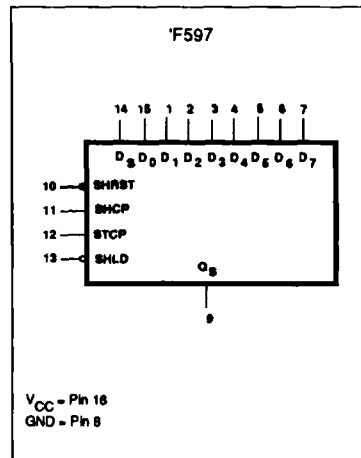
INPUT AND OUTPUT LOADING AND FAN-OUT TABLE

	PINS	DESCRIPTION	74F(U.L.) HIGH/LOW	LOAD VALUE HIGH/LOW
'F597	D_S	Serial data input	1.0/0.033	20 μ A/20 μ A
	D_0 - D_7	Parallel data inputs	1.0/0.033	20 μ A/20 μ A
	SHCP	Shift register clock pulse input	1.0/0.033	20 μ A/20 μ A
	STCP	Storage register clock pulse input	1.0/0.033	20 μ A/20 μ A
	SHLD	Shift register load input (active Low)	1.0/0.033	20 μ A/20 μ A
	SHRST	Shift register reset input (active Low)	1.0/0.033	20 μ A/20 μ A
	Q_S	Serial data output	50/33	1.0mA/20mA
'F598	I/O_n	Parallel data inputs	1.0/0.033	20 μ A/20 μ A
	D_{S0} , D_{S1}	Serial data inputs	1.0/0.033	20 μ A/20 μ A
	SHCP	Shift register clock pulse input	1.0/0.033	20 μ A/20 μ A
	STCP	Storage register clock pulse input	1.0/0.033	20 μ A/20 μ A
	SHCPEN	Shift register clock pulse enable input	1.0/0.033	20 μ A/20 μ A
	SHLD	Shift register load input (active Low)	1.0/0.033	20 μ A/20 μ A
	SHRST	Shift register reset input (active Low)	1.0/0.033	20 μ A/20 μ A
	S	Serial data selector input	1.0/0.033	20 μ A/20 μ A
	OE	Output Enable input	1.0/0.033	20 μ A/20 μ A
	Q_S	Serial data output	50/33	1.0mA/20mA
	I/O_n	Parallel data outputs	150/40	3.0mA/24mA

NOTE:

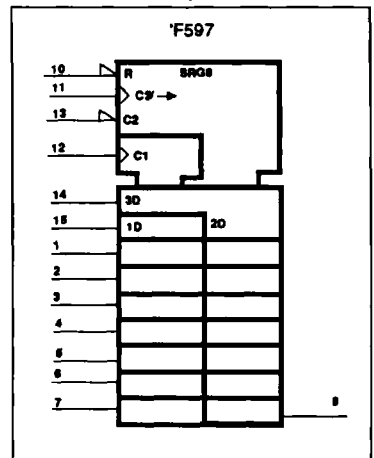
One (1.0) FAST Unit Load is defined as: 20 μ A in the High state and 0.6mA in the Low state.

LOGIC SYMBOL



6-576

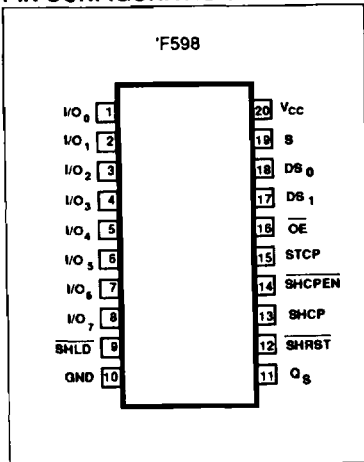
LOGIC SYMBOL (IEEE/IEC)



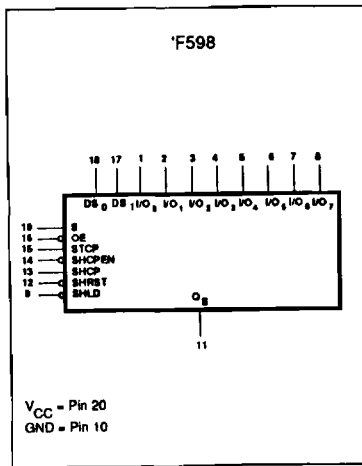
Shift Registers

FAST 74F597, 74F598

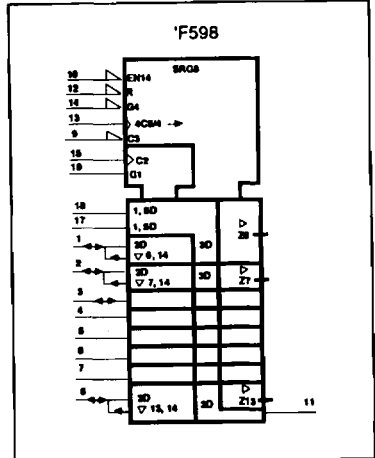
PIN CONFIGURATION



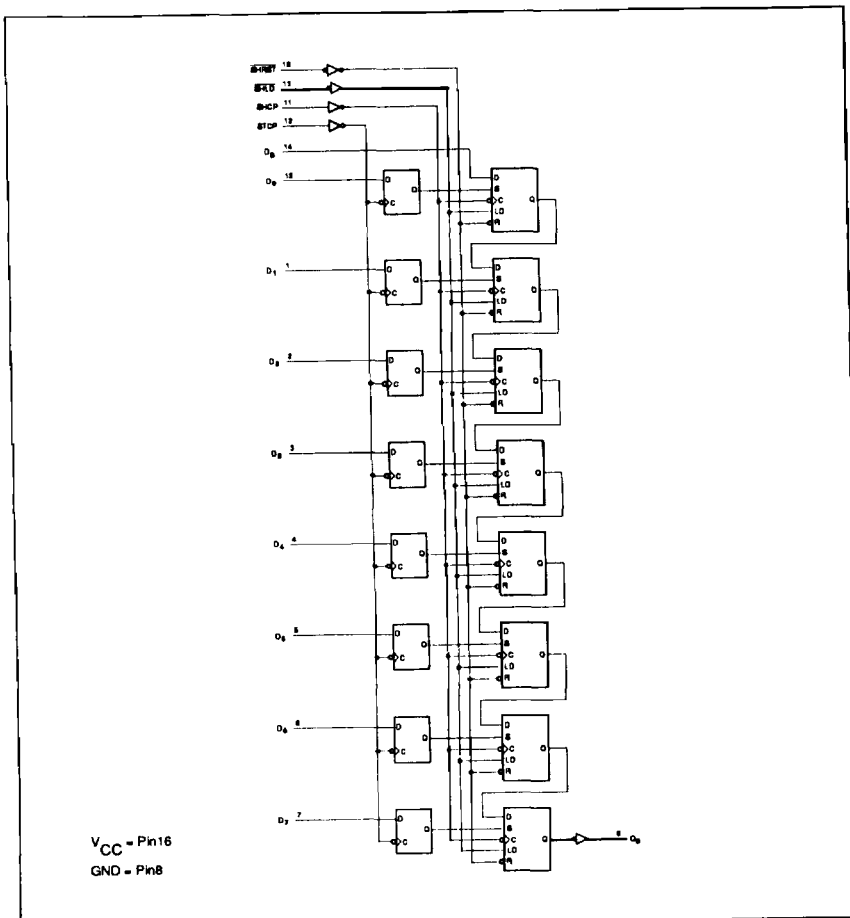
LOGIC SYMBOL



LOGIC SYMBOL (IEEE/IEC)



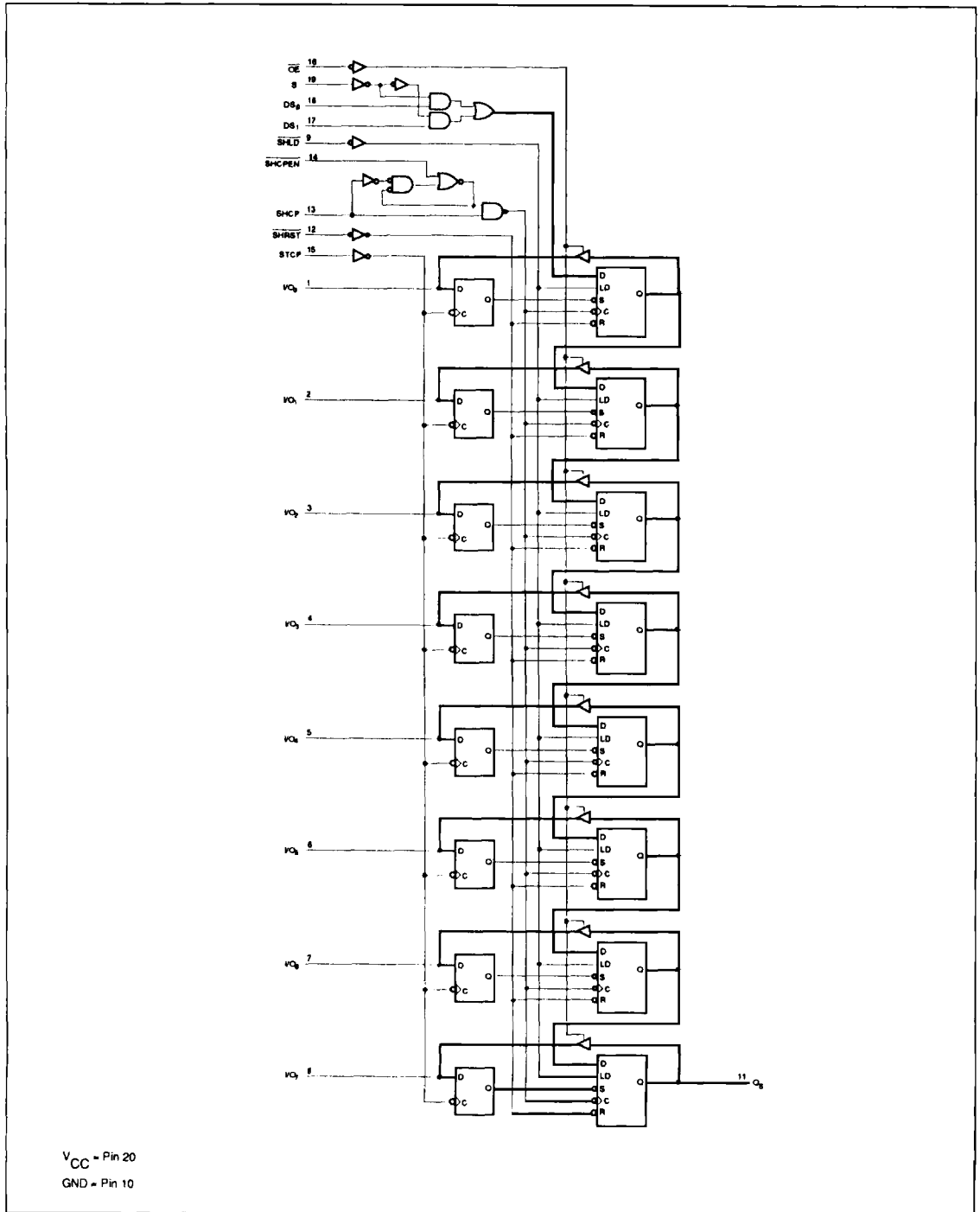
LOGIC DIAGRAM for 'F597



Shift Registers

FAST 74F597, 74F598

LOGIC DIAGRAM FOR 'F598



Shift Registers

FAST 74F597, 74F598

ABSOLUTE MAXIMUM RATINGS (Operation beyond the limits set forth in this table may impair the useful life of the device. Unless otherwise noted these limits are over the operating free-air temperature range.)

SYMBOL	PARAMETER	RATING	UNIT	
V_{CC}	Supply voltage	-0.5 to +7.0	V	
V_{IN}	Input voltage	-0.5 to +7.0	V	
I_{IN}	Input current	-30 to +5	mA	
V_{OUT}	Voltage applied to output in High output state	-0.5 to $+V_{CC}$	V	
I_{OUT}	Current applied to output in Low output state	Q_S	40	mA
		$I/O_0 - I/O_7$	48	mA
T_A	Operating free-air temperature range	0 to +70	°C	
T_{STG}	Storage temperature	-65 to +150	°C	

RECOMMENDED OPERATING CONDITIONS

SYMBOL	PARAMETER	LIMITS			UNIT
		Min	Nom	Max	
V_{CC}	Supply voltage	4.5	5.0	5.5	V
V_{IH}	High-level input voltage	2.0			V
V_{IL}	Low-level input voltage			0.8	V
I_{IK}	Input clamp current			-18	mA
I_{OH}	High-level output current	Q_S		-1	mA
		$I/O_0 - I/O_7$		-3	mA
I_{OL}	Low-level output current	Q_S		20	mA
		$I/O_0 - I/O_7$		24	mA
T_A	Operating free-air temperature range	0		70	°C

Shift Registers

FAST 74F597, 74F598

DC ELECTRICAL CHARACTERISTICS (Over recommended operating free-air temperature range unless otherwise noted.)

SYMBOL	PARAMETER		TEST CONDITIONS ¹			LIMITS			UNIT	
						Min	Typ ²	Max		
V_{OH}	High-level output voltage	Q_S	$V_{CC} = \text{MIN},$ $V_{IL} = \text{MAX},$ $V_{IH} = \text{MIN}$	$I_{OH} = -1\text{mA}$	$\pm 10\%V_{CC}$	2.5			V	
					$\pm 5\%V_{CC}$	2.7	3.4		V	
		I/O_n		$I_{OH} = -3\text{mA}$	$\pm 10\%V_{CC}$	2.4			V	
					$\pm 5\%V_{CC}$	2.7	3.3		V	
V_{OL}	Low-level output voltage		$V_{CC} = \text{MIN},$ $V_{IL} = \text{MAX},$ $V_{IH} = \text{MI}$	$I_{OL} = \text{MAX}$	$\pm 10\%V_{CC}$		0.30	0.50	V	
					$\pm 5\%V_{CC}$		0.30	0.50	V	
V_{IK}	Input clamp voltage		$V_{CC} = \text{MIN}, I_I = I_{IK}$				-0.73	-1.2	V	
I_I	Input current at maximum input voltage	others	$V_{CC} = 0.0V, V_I = 7.0V$					100	μA	
		I/O_n	$V_{CC} = 5.5V, V_I = 5.5V$					1	mA	
I_{IH}	High-level input current		$V_{CC} = \text{MAX}, V_I = 2.7V$					20	μA	
I_{IL}	Low-level input current		$V_{CC} = \text{MAX}, V_I = 0.5V$					-20	μA	
$I_{OZH} + I_{IH}$	Off-state output current High-level voltage applied	I/O_n only	$V_{CC} = \text{MAX}, V_O = 2.7V$					70	μA	
$I_{OZL} + I_{IL}$	Off-state output current Low-level voltage applied		$V_{CC} = \text{MAX}, V_O = 0.5V$					-70	μA	
I_{OS}	Short-circuit output current ³		$V_{CC} = \text{MAX}$				-60	-150	mA	
I_{CC}	Supply current (total)	'F597	I_{CCH}	$V_{CC} = \text{MAX}$				45	70	mA
			I_{CCL}					48	75	mA
		'F598	I_{CCH}					75	90	mA
			I_{CCL}					78	95	mA
			I_{CCZ}					85	100	mA

NOTES:

- For conditions shown as MIN or MAX, use the appropriate value specified under recommended operating conditions for the applicable type.
- All typical values are at $V_{CC} = 5V, T_A = 25^\circ\text{C}$.
- Not more than one output should be shorted at a time. For testing I_{OS} , the use of high-speed test apparatus and/or sample-and-hold techniques are preferable in order to minimize internal heating and more accurately reflect operational values. Otherwise, prolonged shorting of a High output may raise the chip temperature well above normal and thereby cause invalid readings in other parameter tests. In any sequence of parameter tests, I_{OS} tests should be performed last.

Shift Registers

FAST 74F597, 74F598

AC ELECTRICAL CHARACTERISTICS for 'F597

SYMBOL	PARAMETER	TEST CONDITION	LIMITS					UNIT
			$T_A = +25^\circ\text{C}$ $V_{CC} = 5\text{V}$ $C_L = 50\text{pF}$ $R_L = 500\Omega$			$T_A = 0^\circ\text{C to } +70^\circ\text{C}$ $V_{CC} = 5\text{V} \pm 10\%$ $C_L = 50\text{pF}$ $R_L = 500\Omega$		
			Min	Typ	Max	Min	Max	
f_{MAX}	Maximum clock frequency	Waveform 1	100	120		80		MHz
t_{PLH} t_{PHL}	Propagation delay SHCP to Q_S	Waveform 1	4.0 4.0	6.5 7.0	8.5 9.0	4.0 4.0	9.5 10.0	ns
t_{PLH} t_{PHL}	Propagation delay $\overline{\text{SHLD}}$ to Q_S	Waveform 1	4.0 4.0	7.5 8.0	9.5 10.0	4.0 4.0	10.0 11.0	ns
t_{PLH} t_{PHL}	Propagation delay STCP to Q_S	Waveform 1	4.0 4.0	7.5 8.0	9.5 10.0	4.0 4.0	10.0 11.0	ns
t_{PHL}	Propagation delay, $\overline{\text{SHRST}}$ to Q_S	Waveform 3	4.0	8.0	10.0	4.0	11.0	ns

AC SETUP REQUIREMENTS for 'F597

SYMBOL	PARAMETER	TEST CONDITION	LIMITS					UNIT
			$T_A = +25^\circ\text{C}$ $V_{CC} = 5\text{V}$ $C_L = 50\text{pF}$ $R_L = 500\Omega$			$T_A = 0^\circ\text{C to } +70^\circ\text{C}$ $V_{CC} = 5\text{V} \pm 10\%$ $C_L = 50\text{pF}$ $R_L = 500\Omega$		
			Min	Typ	Max	Min	Max	
$t_s(\text{H})$ $t_s(\text{L})$	Setup time, High or Low D_S to SHCP	Waveform 3	3.0 3.0			3.0 3.0		ns
$t_h(\text{H})$ $t_h(\text{L})$	Hold time, High or Low D_S to SHCP	Waveform 3	1.0 1.0			1.0 1.0		ns
$t_s(\text{H})$ $t_s(\text{L})$	Setup time, High or Low STCP to $\overline{\text{SHLD}}$	Waveform 4	3.0 3.0			3.0 3.0		ns
$t_h(\text{H})$ $t_h(\text{L})$	Hold time, High or Low STCP to $\overline{\text{SHLD}}$	Waveform 4	1.0 1.0			1.0 1.0		ns
$t_w(\text{H})$ $t_w(\text{L})$	SHCP pulse width, High or Low	Waveform 1	4.0 5.0			4.0 5.0		ns
$t_w(\text{H})$ $t_w(\text{L})$	STCP pulse width, High or Low	Waveform 1	4.0 5.0			4.0 5.0		ns
$t_w(\text{L})$	$\overline{\text{SHRST}}$ pulse width, Low	Waveform 1	4.0			4.0		ns
$t_w(\text{L})$	$\overline{\text{SHLD}}$ pulse width, Low	Waveform 1	4.0			4.0		ns
t_{REC}	Recovery time, $\overline{\text{SHRST}}$ to SHCP	Waveform 2	6.0			7.0		ns
t_{REC}	Recovery time, $\overline{\text{SHLD}}$ to SHCP	Waveform 2	6.0			7.0		ns

Shift Registers

FAST 74F597, 74F598

AC ELECTRICAL CHARACTERISTICS for 'F598

SYMBOL	PARAMETER	TEST CONDITION	LIMITS					UNIT
			$T_A = +25^\circ\text{C}$ $V_{CC} = 5\text{V}$ $C_L = 50\text{pF}$ $R_L = 500\Omega$			$T_A = 0^\circ\text{C to } +70^\circ\text{C}$ $V_{CC} = 5\text{V } \pm 10\%$ $C_L = 50\text{pF}$ $R_L = 500\Omega$		
			Min	Typ	Max	Min	Max	
f_{MAX}	Maximum clock frequency	Waveform 1	100	120		80		MHz
t_{PLH} t_{PHL}	Propagation delay SHCP to Q_S	Waveform 1	4.0 4.0	6.5 7.0	8.5 9.0	4.0 4.0	9.5 10.5	ns
t_{PLH} t_{PHL}	Propagation delay STCP to Q_S ($\overline{\text{SHLD}} = \text{Low}$)	Waveform 1	4.0 4.0	7.5 8.0	9.5 10.0	4.0 4.0	10.0 11.0	ns
t_{PLH} t_{PHL}	Propagation delay SHLD to Q_S	Waveform 1	4.0 4.0	7.5 8.0	9.0 9.0	4.0 4.0	10.0 11.0	ns
t_{PLH} t_{PHL}	Propagation delay SHCP to I/O_n	Waveform 1	4.0 4.0	7.0 7.0	9.0 9.0	4.0 4.0	10.5 10.5	ns
t_{PLH} t_{PHL}	Propagation delay $\overline{\text{SHLD}}$ to I/O_n	Waveform 1	4.0 4.0	7.0 7.0	9.0 9.0	4.0 4.0	10.0 10.0	ns
t_{PHL}	Propagation delay, $\overline{\text{SHRST}}$ to I/O_n	Waveform 2	4.0	8.0	10.0	4.0	11.0	ns
t_{PHL}	Propagation delay, $\overline{\text{SHRST}}$ to Q_S	Waveform 2	4.0	8.0	10.0	4.0	11.5	ns
t_{PZH} t_{PZL}	Output Enable time to High or Low level	Waveform 5 Waveform 6	4.0 4.0	7.5 7.5	9.0 9.0	4.0 4.0	10.5 10.5	ns
t_{PHZ} t_{PLZ}	Output Disable time from High or Low level	Waveform 5 Waveform 6	3.0 3.0	6.0 6.0	8.0 8.0	3.0 3.0	9.0 9.0	ns

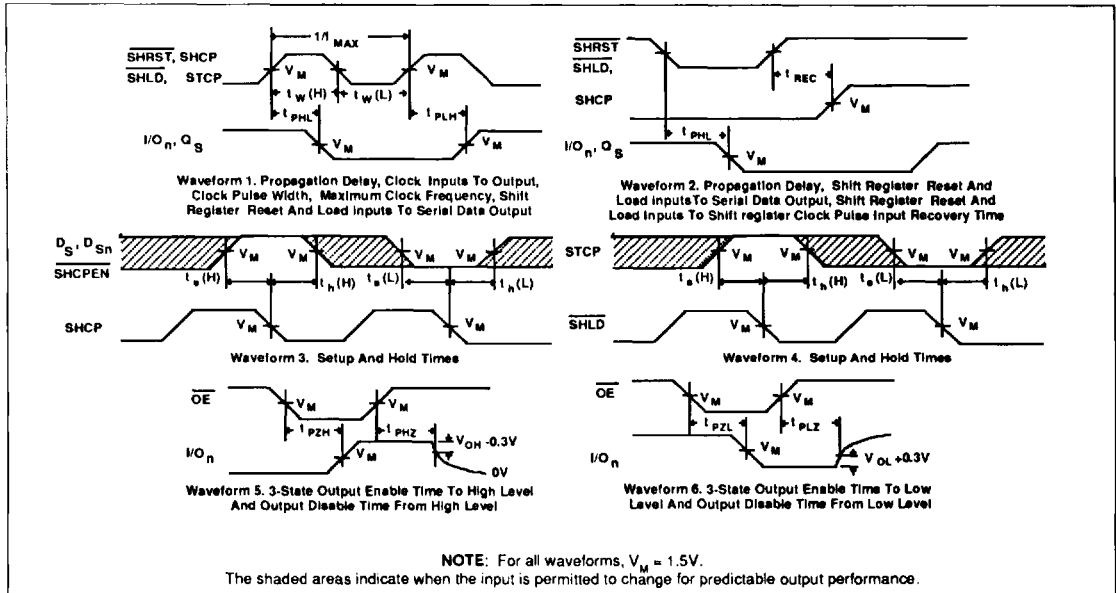
AC SETUP REQUIREMENTS for 'F598

SYMBOL	PARAMETER	TEST CONDITION	LIMITS					UNIT
			$T_A = +25^\circ\text{C}$ $V_{CC} = 5\text{V}$ $C_L = 50\text{pF}$ $R_L = 500\Omega$			$T_A = 0^\circ\text{C to } +70^\circ\text{C}$ $V_{CC} = 5\text{V } \pm 10\%$ $C_L = 50\text{pF}$ $R_L = 500\Omega$		
			Min	Typ	Max	Min	Max	
$t_s(H)$ $t_s(L)$	Setup time, High or Low D_{Sn} to SHCP	Waveform 3	3.0 3.0			3.0 3.0		ns
$t_h(H)$ $t_h(L)$	Hold time, High or Low D_{Sn} to SHCP	Waveform 3	1.0 1.0			1.0 1.0		ns
$t_s(H)$ $t_s(L)$	Setup time, High or Low STCP to SHLD	Waveform 4	3.0 3.0			3.0 3.0		ns
$t_h(H)$ $t_h(L)$	Hold time, High or Low STCP to SHLD	Waveform 4	1.0 1.0			1.0 1.0		ns
$t_s(H)$ $t_s(L)$	Setup time, High or Low SHCPEN to SHCP	Waveform 3	6.0 6.0			6.0 6.0		ns
$t_w(H)$ $t_w(L)$	SHCP pulse width, High or Low	Waveform 1	4.0 5.0			4.0 5.0		ns
$t_w(H)$ $t_w(L)$	STCP pulse width, High or Low	Waveform 1	4.0 5.0			4.0 5.0		ns
$t_w(L)$	$\overline{\text{SHRST}}$ pulse width, Low	Waveform 1	4.0			4.0		ns
$t_w(L)$	$\overline{\text{SHLD}}$ pulse width, Low	Waveform 1	4.0			4.0		ns
t_{REC}	Recovery time, $\overline{\text{SHRST}}$ to SHCP	Waveform 2	6.0			7.0		ns
t_{REC}	Recovery time, $\overline{\text{SHLD}}$ to SHCP	Waveform 2	6.0			6.0		ns

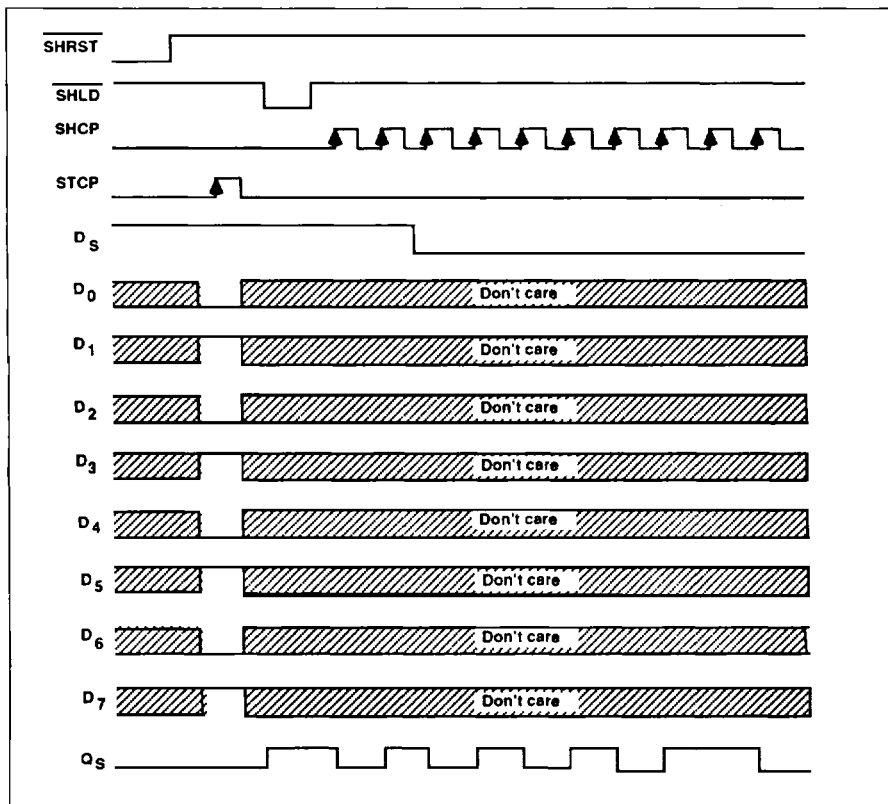
Shift Registers

FAST 74F597, 74F598

AC WAVEFORMS



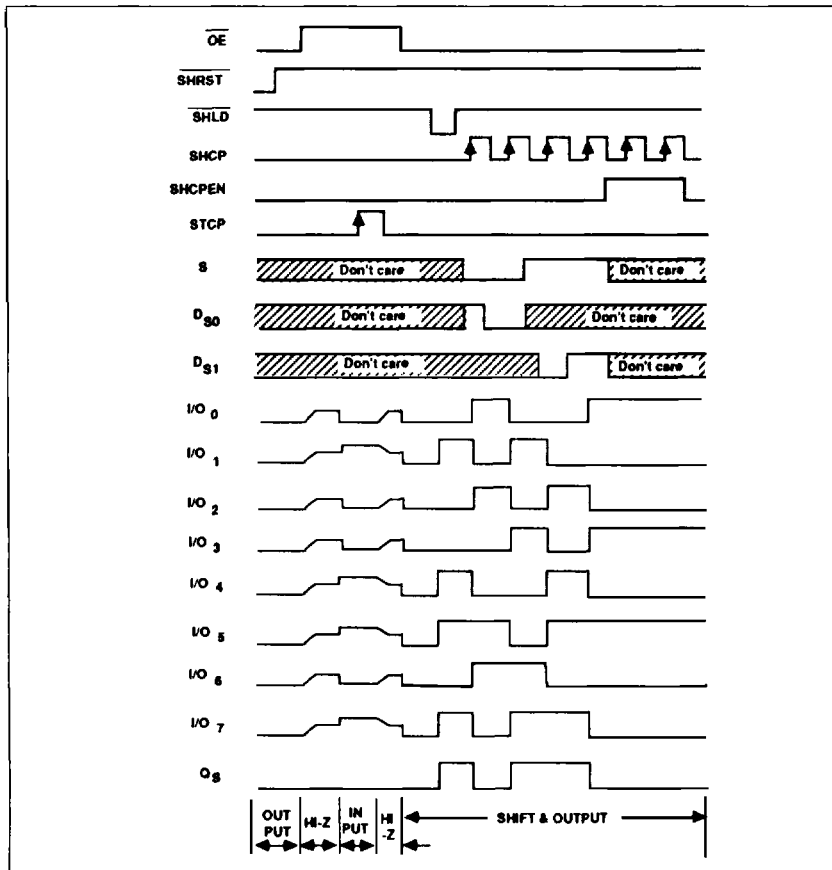
TYPICAL TIMING DIAGRAM for 74F597



Shift Registers

FAST 74F597, 74F598

TYPICAL TIMING DIAGRAM for 74F598



TEST CIRCUIT AND WAVEFORMS

